

IN THE SPECIFICATION:

Please insert the following paragraph at the beginning of the specification.

This application is a 371 of international application PCT/JP2005/002398, which claims priority based on Japanese patent application Nos. 2004-039461 and 2004-040930 filed February 17 and February 18, 2004, respectively, which are incorporated herein by reference.

Please replace the paragraph beginning on page 23, line 19, with the following rewritten paragraph:

K. Estimation of microplanarity due to heat treatment:

The heat treatment was carried out by leaving a film for 24 hours in an oven controlled at 100 °C. The microplanarities of layer (A) before and after the heat treatment were determined at a measurement area magnification of 41.6 times and an area for measurement of 239 x 239 μ m (0.057 mm²) using a non-contact type three dimensional roughness meter TOPO-3D manufactured by WYKO Corporation. By an analyzing soft (ver. 4.90) incorporated into the roughness meter, the relative powers at spatial frequencies of ~~10 cm⁻¹ and 200 cm⁻¹~~ 10 mm⁻¹ and 200 mm⁻¹ were determined. The

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measurement was carried out ten times, and the average value was defined as the relative power. As to WRa, only the film before the heat treatment was measured.